

IGBT Chip in NPT-technology

Features:

- 1200V NPT technology
- low turn-off losses
- positive temperature coefficient
- easy paralleling

This chip is used for:

 power module BUP 314

Applications:

drives



Chip Type	V _{CE}	<i>I</i> c	Die Size	Package
SIGC42T120C	1200V	25A	6.59 x 6.49 mm ²	sawn on foil

Mechanical Parameter

Raster size	6.59 x 6.49			
Emitter pad size	2 x (1.58 x 2.18)	mm ²		
Gate pad size	1.06 x 0.65			
Area total	42.8	7		
Thickness	200	μm		
Wafer size	150	mm		
Max.possible chips per wafer	334			
Passivation frontside	ssivation frontside Photoimide			
Pad metal	3200 nm AlSiCu			
Backside metal	Ni Ag –system suitable for epoxy and soft solder die bonding			
Die bond	Electrically conductive glue or solder			
Wire bond	Al, <500μm			
Reject ink dot size	Ø 0.65mm ; max 1.2mm			
Recommended storage environment	Store in original container, in dry nitrogen, in dark environment, < 6 month at an ambient temperature of 23°C			



Maximum Ratings

Parameter	Symbol	Value	Unit		
Collector-Emitter voltage, $T_{\rm vj}$ =25 °C	V _{CE}	1200	V		
DC collector current, limited by $T_{\rm vj\;max}$	I _C	1)	Α		
Pulsed collector current, $t_{\rm p}$ limited by $T_{\rm vj\;max}$	I _{c,puls}	75	Α		
Gate emitter voltage	V _{GE}	±20	V		
Junction temperature range	T _{vj}	-55 + 175	°C		
Operating junction temperature	T _{vj}	-55+150	°C		
Short circuit data 2) V_{GE} = 15V, V_{CC} = 900V, T_{vj} = 150°C	tsc	10	μs		
Reverse bias safe operating area ² (RBSOA)	I _{C,max} = 50A, V _{CE,max} = 1200V		/		
Neverse bias sale operating area (NBSOA)	<i>T</i> _{vj} ≤ 150°C				

¹⁾ depending on thermal properties of assembly

Static Characteristic (tested on wafer), T_{vj} =25 °C

Parameter	Symbol	Conditions	Value			Unit
i didilietei	Symbol	Conditions	min.	typ.	typ. max.	
Collector-Emitter breakdown voltage	V _{(BR)CES}	$V_{\rm GE}$ =0V , $I_{\rm C}$ = 1.5mA	1200			
Collector-Emitter saturation voltage	V _{CEsat}	V _{GE} =15V, I _C =25A	2.0	2.5	3.0	V
Gate-Emitter threshold voltage	$V_{GE(th)}$	$I_{\rm C}$ =1mA , $V_{\rm GE}$ = $V_{\rm CE}$	4.5	5.5	6.5	
Zero gate voltage collector current	I _{CES}	V _{CE} =1200V , V _{GE} =0V			3.1	μΑ
Gate-Emitter leakage current	I _{GES}	V _{CE} =0V , V _{GE} =20V			120	nA
Integrated gate resistor	$r_{\rm G}$			none		Ω

$\textbf{Dynamic Characteristic} \ (\text{not subject to production test - verified by design / characterization}),$

*T*_{vj} =25 °C

Parameter	Symbol	Conditions	Value			Unit
raiametei	Symbol	Conditions	min.	typ.	max.	Ullit
Input capacitance	Cies	V _{CE} =25V,		1650		
Output capacitance	Coes	$V_{GE}=0V$,		250		pF
Reverse transfer capacitance	C _{res}	f=1MHz		110		

²⁾ not subject to production test - verified by design/characterization

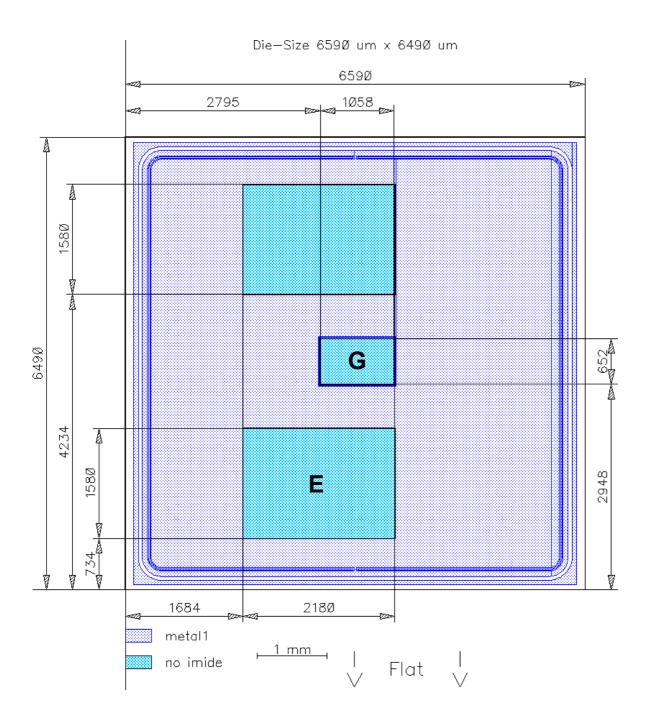


Further Electrical Characteristic

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.



Chip Drawing



E = Emitter pad

G = Gate pad



Description

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Published by Infineon Technologies AG 81726 Munich, Germany © 2008 Infineon Technologies AG All Rights Reserved.

Legal Disclaimer

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics. With respect to any examples or hints given herein, any typical values stated herein and/or any information regarding the application of the device, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation, warranties of non-infringement of intellectual property rights of any third party.

Information

For further information on technology, delivery terms and conditions and prices, please contact the nearest Infineon Technologies Office (www.infineon.com).

Warnings

Due to technical requirements, components may contain dangerous substances. For information on the types in question, please contact the nearest Infineon Technologies Office. Infineon Technologies components may be used in life-support devices or systems only with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.